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(54) **Title:** PROBES, PROBE BLADES, TOOLS FOR PROBE BLADES, BLADE HOLDERS, AND PROBE SYSTEMS FOR ELECTRICALLY TESTING A DEVICE UNDER TEST

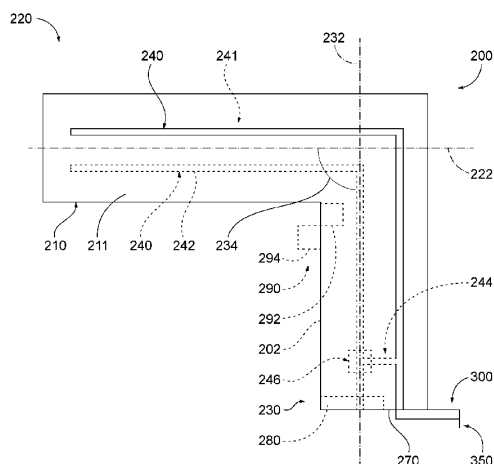


FIG. 4

(57) **Abstract:** Probes, probe blades, tools for probe blades, blade holders, and probe systems for electrically testing a device under test (DUT). In some examples, the probe blades are configured to provide a Kelvin electrical connection with the DUT. In some examples, the probe blades include an alignment structure configured to engage with a blade holder when the probe blade is received within a blade -receiving region of the blade holder. The blade holders are configured to separably and operatively attach a probe blade to a probe system. In some examples, the blade holders include the probe blade. The probe systems are configured to electrically test the DUT and include the blade holder.

LU, LV, MC, ME, MK, MT, NL, NO, PL, PT, RO, RS, SE,
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